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**SERIAL NO. 09/740,393**

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NT & TRADEMARK

**FILING DATE: 12/18/00**

**GROUP**

**U.S. PATENT DOCUMENTS**

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## FOREIGN PATENT DOCUMENTS

[illegible]

EXAMINER Mark Weber

5-14/05 DATE

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

PATENT & TRADEMARK Form PTO-1449 (Modified)  LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	ATTY. DOCKET NO. 395D US	SERIAL NO. 09/740,393
	APPLICANT: Metcalf et al.	
	FILING DATE: 12/18/00	GROUP

## OTHER ART

[illegible]

• a copy of this reference is not provided as it was previously cited by or submitted to the office in the related case, Patent Application No. \_\_\_\_\_, filed \_\_\_\_\_ and relied upon under 35 U.S.C. 120.

EXAMINER	DATE CONSIDERED
<i>Mark Breen</i>	<i>5/4/05</i>

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### U.S. PATENT DOCUMENTS

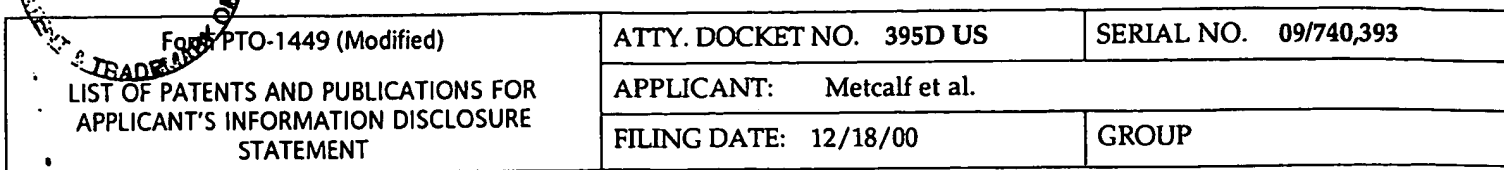
Exam Init	Ref Des	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
MB		5,663,159	9/2/1997	Starrett Jr., et al.			
MB		6,107,300	8/22/2000	Bakthavatchalam et al.			
MB		6,255,485	7/3/2001	Gray et al.			
MB		6,573,044	6/3/2003	Gray et al.			
MB		6,767,906	7/27/2004	Imbach et al.			
MB		6,838,559	1/4/2005	Vaccaro et al.			
MB		2003/0187261	10/2/2003	Havlicek et al.			
MB		2004/0157864	8/12/2004	Wu et al.			

### FOREIGN PATENT DOCUMENTS

Exam Init	Ref Des	Country & Doc. No. (11)	Pub. Date (43)	Name	Class	Sub Class	Translation Yes No	
MB		WO 00/44750	8/3/2000	Lum et al.				

EXAMINER <i>Mark K. Beyer</i>	DATE CONSIDERED <i>5/4/05</i>
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## Author, Publication, Pertinent Pages, Date

[illegible]

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